

L Number	Hits	Search Text	DB	Time stamp
2	144	(703/28).CCLS.	USPAT	2004/09/19 14:37
3	0	network and device and diagnostic\$2 and (ISC adj pins)	USPAT	2004/09/19 14:38
4	0	network and device and diagnostic\$2 and (ISC same pins)	USPAT	2004/09/19 14:38
5	48	network and device and diagnostic\$2 and ISC	USPAT	2004/09/19 14:39
6	730	diagnostic same embedded	USPAT	2004/09/19 14:40
7	25	(diagnostic same embedded) and JTAG	USPAT	2004/09/19 14:45
8	10	FPGA and remote and diagnostics and JTAG	USPAT	2004/09/19 14:54
9	1	BIST and diagnostic\$2 and FPGA and embedded and boundary and scan and testbench	USPAT	2004/09/19 14:54

Untitled

Krzysztof Badzmirowski et al., "Diagnosis of Digital/Analogue Measurement System with Application of Test Bus and Distributed Diagnostic Subsystem,"
Proceedings of the IEEE Instrumentation and Measurement Technology Conference,
1998.

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Computer aided verification and diagnosis of distributed measurement systems

Badzmirowski, K.; Kern, J.; Liderman, K.; Zielinski, Z.;

Instrumentation and Measurement Technology Conference, 1997. IMTC/97. Proceedings. 'Sensing, Processing, Networking'. IEEE , Volume: 2 , 19-21 May 1997

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2 The measurement quality verification process with application of distributed expert systems

Badzmirowski, K.; Kern, J.; Liderman, K.; Zielinski, Z.;

Instrumentation and Measurement Technology Conference, 1996. IMTC-96. Conference Proceedings. 'Quality Measurements: The Indispensable Bridge between Theory and Reality'. IEEE , Volume: 2 , 1996

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3 The issue of diagnosis quality applied to a distributed system of digital signal microanalyzers, equipped with standard test ports

Badzmirowski, K.; Kern, J.;

Instrumentation and Measurement Technology Conference, 1999. IMTC/99. Proceedings of the 16th IEEE , Volume: 1 , 24-26 May 1999

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4 Application of deterministic dither signals in digital voltmeter with sigma-delta oversampled A/D converter

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Instrumentation and Measurement Technology Conference, 1999. IMTC/99. Proceedings of the 16th IEEE , Volume: 3 , 24-26 May 1999

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5 Diagnosis of digital/analogue measurement system with application of test bus and distributed diagnostic subsystem

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Instrumentation and Measurement Technology Conference, 1998. IMTC/98. Conference Proceedings. IEEE , Volume: 1 , 18-21 May 1998

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6 Effects of noise dither signals on differential linearity and effective resolution of sigma-delta A/D converters in measuring applications

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7 Effectiveness of various dithering architectures for linearisation of high-resolution oversampling A/D converters

Badzmirowski, K.; Jackiewicz, B.;

Advanced A/D and D/A Conversion Techniques and their Applications, 1999. Third International Conference on (Conf. Publ. No. 466) , 27-28 July 1999

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